

Journals & Magazines > IEEE Transactions on Reliabil... > Volume: 58 Issue: 1 ?

General Distributional Properties of Discounted Warranty Costs With Risk Adjustment Under Minimal Repair

Publisher: IEEE

Cite This

PDF

Thierry Duchesne ; Fouad Marri All Authors

5Cites in Papers

137Full Text Views

Manage Content Alerts

Add to Citation Alerts

| | |
|----------------|--|
| Abstract | <div><div>Down</div><div>PDF</div></div> |
| Authors | |
| References | <div><div>Abstract:</div><div>We study the distributional properties (mean, variance, characteristic function) of the discounted warranty cost (DWC) for general warranty programs including free repla... View more</div></div> |
| Citations | |
| Keywords | <div><div>► Metadata</div><div><div>Abstract:</div><div>We study the distributional properties (mean, variance, characteristic function) of the discounted warranty cost (DWC) for general warranty programs including free replacement (FRW), pro rata (PRW), and FRW/PRW in the context of minimal repair. Because only failure times & types are needed in the derivation of these properties, the reliability of the systems is modeled according to a general</div></div></div> |
| Metrics | |
| More Like This | |

This website utilizes technologies such as cookies to enable essential site functionality, as well as for analytics, personalization, and targeted advertising purposes. You may change your settings at any time or accept the default settings. You may close this banner to continue with only essential cookies.

Privacy Policy

Storage Preferences

Targeted Advertising

Personalization

Analytics

Save

Accept All

Reject All

| | |
|------------|---|
| Authors | ▼ |
| References | ▼ |
| Citations | ▼ |
| Keywords | ▼ |
| Metrics | ▼ |

This website utilizes technologies such as cookies to enable essential site functionality, as well as for analytics, personalization, and targeted advertising purposes. You may change your settings at any time or accept the default settings. You may close this banner to continue with only essential cookies. [Privacy Policy](#)

Storage Preferences

- ☐ Targeted Advertising
- ☐ Personalization
- ☐ Analytics

Save

Accept All

Reject All

| | | | |
|--------------------------|--------------------------|----------------------------|------------------------------|
| CHANGE USERNAME/PASSWORD | VIEW PURCHASED DOCUMENTS | COMMUNICATIONS PREFERENCES | US & CANADA: +1 800 678 4333 |
| | | PROFESSION AND EDUCATION | WORLDWIDE: +1 732 981 0060 |
| | | TECHNICAL INTERESTS | CONTACT & SUPPORT |

[About IEEE Xplore](#) [Contact Us](#) [Help](#) [Accessibility](#) [Terms of Use](#) [Nondiscrimination Policy](#) [IEEE Ethics Reporting](#) [Sitemap](#) [IEEE Privacy Policy](#)

IEEE Account

- » [Change Username/Password](#)
- » [Update Address](#)

Purchase Details

- » [Payment Options](#)
- » [Order History](#)
- » [View Purchased Documents](#)

Profile Information

- » [Communications Preferences](#)
- » [Profession and Education](#)
- » [Technical Interests](#)

Need Help?

- » **US & Canada:** +1 800 678 4333
- » **Worldwide:** +1 732 981 0060
- » [Contact & Support](#)

[About IEEE Xplore](#) [Contact Us](#) [Help](#) [Accessibility](#) [Terms of Use](#) [Nondiscrimination Policy](#) [Sitemap](#) [Privacy & Opting Out of Cookies](#)

A not-for-profit organization, IEEE is the world's largest technical professional organization dedicated to advancing technology for the benefit of humanity.
© Copyright 2024 IEEE - All rights reserved. Use of this web site signifies your agreement to the terms and conditions.

This website utilizes technologies such as cookies to enable essential site functionality, as well as for analytics, personalization, and targeted advertising purposes. You may change your settings at any time or accept the default settings. You may close this banner to continue with only essential cookies. [Privacy Policy](#)

Storage Preferences

- ☐ Targeted Advertising
- ☐ Personalization
- ☐ Analytics

Save

Accept All

Reject All